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REV											┢		-			<b> </b>			╞		t –			
SHEET											$\square$	Π												
REV STATUS OF SHEETS	F	RE	V	•	1	2	3	4	5	6	7	8	9	$\square$				$\overline{ }$						
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THIS DRAWIN FOR USE BY AL AND AGEN	L DE	PART	MEN 1E	τs	ļ			AUGU		ATE 1988			Ţ	size A			cage coi 6 <b>726</b>			59	62	-88	364	17
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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE 1.1 Scope. This drawing describes devic ith 1.2.1 of MIL_STD×883, "Provisions for on-JAN devices".	the use of MIL▲STD-4	383 in conjun	ction with compliant	
1.2 <u>Part number</u> . The complete part number of the second	G   	utline .2)	X I I Lead finish per MIL-M≏38510	
01 LT10218M-7 7.0	<u>Circuit function</u> V voltage reference V voltage reference	∆ <sup>V</sup> OUT(V) *.05 V *.05 V	Δ¥ <sub>OUT</sub> /ΔT(ppm/°C) 5.0 20	as
<u>Outline letter</u> G	<u>Case</u> A-1(8-lead, .370"	<u>outline</u> X .185"), can	package	
Input voltage	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	50°C/W 175°C	O, appendix C	
/ Shunt mode current limit.	· · · · · · · · · · · · · · · · · · ·			
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2. APPLICABLE DOCUMENTS

2.1 <u>Government specification and standard</u>. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein. SPECIFICATION MILITARY MIL-M-38510 - Microcircuits, General Specification for STANDARD MILITARY MIL-STD-883 - Test Methods and Procedures for Microelectronics (Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.) 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence. 3. REQUIREMENTS 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein. 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein. 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1. 3.2.2 Case outline. The case outline shall be in accordance with 1.2.2 herein. 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range. 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein. STANDARDIZED SIZE A 5962-88647 MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER **REVISION LEVEL** SHEET DAYTON, OHIO 45444 DESC FORM 193A SEP 87 ☆ U. S. GOVERNMENT PRINTING OFFICE: 1988-549-904

Test	Symbol	C -55°C V <sub>IN</sub> = 12 unless of	conditions < T <sub>A</sub> <u>&lt;</u> +125°C, V, I <sub>OUT</sub> = 0 mA cherwise specifi	Group A subgroups	Device types	L1 Min	mits   Max   	Unit
Output voltage <u>1</u> /	Vouт	T <sub>A</sub> = +25°C		1	  A11 	  6.95 	7.05	v
)utput voltage :emperature coefficient	Δ¥ουτ/ ΔT	T <sub>A</sub> = +125°(	C, -55℃	2,3	01	1 1 1	5.0	ppm/°C
2/					02		20	
ine regulation $\underline{3}/$	V <sub>RLN</sub>	8.5 V <u>&lt;</u> V <sub>IN</sub>	<u>≺</u> 12 V	1	A11		4.0	ppm/V
				2,3	A11		8.0	Ť
	• • •	12 V <u>&lt;</u> V <sub>IN</sub>	<u>&lt;</u> 40 V	1			2.0	
				2,3	  A11	   	4.0	+
Load regulation (sourcing mode) <u>3</u> /	V <sub>RLD1</sub>	0 <u>≺</u> I <sub>OUT</sub> <u>≺</u>	10 mA	1 A11			25	ppm/mA
(sourcing moder or				2,3	A11		40	
Load regulation (shunt mode) <u>3/ 4</u> /	V <sub>RLD2</sub>	1.2 mA <u>&lt;</u> I <sub>S</sub>	HUNT $\leq 10$ mA,	1	A11		100	
				2,3	A11		150	
Supply current (series mode)	1 <sup>1</sup> CC		<u></u> ,	1	A11		1.2	mA
				2,3	A11		1.5	
See footnotes at end of				<b>T</b>				
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Test	Symbol	-55°	Condition C < T <sub>A</sub> <u>&lt;</u> + 2 V, I <sub>OUT</sub> otherwise	125°C.	Group A subgroups			imits   Max     	Unit
Minimum current (shunt mode)	IMIN	V <sub>IN</sub> = Open			1 1	I 41 1		1.0	mA
		   			2,3	1 [A] ]		1.2	T I I
Output voltage noise 5/	NO	10 Hz <u>&lt;</u> f <sub>0</sub>	<u>&lt;</u> 1.0 kHz	, T <sub>A</sub> = +25	5°C 4	A11		4.0	  μV m 
Long term stability of output voltage <u>6</u> /	ΔV <sub>OUT</sub> /	t = 1000 h	rs, T <sub>A</sub> = +	25°C	4	A11 		60	ppm
1/ Output voltage is m less than 0.005 per	easured cent.	immediately	after tur	n-on. Cha	inges due to	chip waı	m−up a	are typ	ically
<ul> <li>2/ Temperature coeffic range by the change and +25°C to +125°C</li> <li>3/ Line and load regul</li> </ul>	in temp . Incre	erature. S mental slop	eparate te e is also	sts are do measured a	one for hot a it +25°C.	nd cold	; -55 (	C to +2	5°C,
change must be take	n into a	ccount sepa	rately. P	ackage the	ermal resista	nce is :	L50°C/W	N.	
4/ Shunt mode regulati current can be redu	on is me ced to O	asured with mA. Load	the input regulation	open. Wi will rema	th the input in the same.	connect	ted, sł	hunt mo	de
5/ RMS noise is measur 1 kHz. The resulti making the final re from average to rms	ng outpu ading an	t is full wa average as	ave rectif opposed t	ied and th orms. Co	en integrate prrection fac	d for a tors are	fixed	period	•
5/ Guaranteed if not t	ested.								
3.6 <u>Certificate of c</u> (see 3.1 herein) shall	onforman be provi	<u>ce</u> . A cert ded with ea	ificate of ch lot of	conformar microcircu	nce as requir lits delivere	ed in Mi d to th	IL-STD is draw	-883 wing.	
3.7 <u>Notification of</u> accordance with MIL-STD	<u>change</u> . -883 (se			ge to DESC	-ECS shall b	e requi	red in		
3.8 <u>Verification and</u> option to review the ma documentation shall be	nufactur	er's facili	ty and app	licable re	equired docum	entatio	etain t 1. Off	the fshore	
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   Device ty	pes 0	1 and 02		
Case out		G		
Termina number		erminal i symbol i		
1		NC see note)		
2		ut voltage     NC   GND   		
5	( Out	NC see note) but voltage		
8		NC   see note)   NC   see note)		
int	ernally. ernal circ	e connected Do not connect uitry to these		
<b>ETCUDE 1</b>	Terminal	connections.		
FIGURE 1.			······································	<u></u>
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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
  - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^{\circ}C$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5, 6, 7, 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life, test method 1005 of MIL-STD-883 conditions:
  - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^{\circ}C$ , minimum.
  - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 4
Group A test requirements (method 5005)	1, 2, 3, 4
Groups C and D end-point electrical parameters (method 5005)	1

TABLE II. Electrical test requirements.

\* PDA applies to subgroup 1.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 <u>Approved source of supply</u>. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing   part number	Vendor CAGE number	Vendor similar part number <u>1</u> /
5962-8864701GX	64155	LT1021BMH-7/883B
5962-8864702GX	64155	LT1021DMH-7/883B

 $\frac{1}{1}$  <u>Caution.</u> Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number Vendor name and address

64155

Linear Technology Corporation 1630 McCarthy Boulevard Milpitas, CA 95035-7487

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